Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/771,338	KIM, JONG HEON	
Examiner	Art Unit	
KHAI TRAN	2611	

SEARCHED					
Class	Subclass	Date	Examiner		
375	148,130 147,149 141,347 349	2/5/2008	кт		
455	101,132	2/5/2008	кт		
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		DATE	EXMR
EAST Search Inventor Name Search		2/5/2008	KT
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